

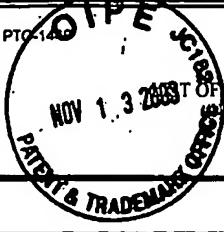
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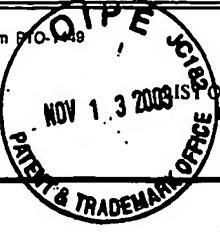
Form PTO-1449			U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2356		priority SERIAL NO. 10/364,054	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			APPLICANT Luan C. Tran					
			priority FILING DATE February 10, 2003		priority GROUP 2812			
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
9U	AA	6,458,666 B2	10-2002	Wasshuber				
9U	AB	6,444,548 B2	09-2002	Divakaruni et al.				
9U	AC	3,886,003	05-1975	Takagi et al.				
9U	AD	4,366,338	12-1982	Turner et al.				
9U	AE	6,008,115	12-1999	Jung				
9U	AF	6,506,647 B2	01-2003	Kuroda et al.				
9U	AG	US2001/0036713A1	11-01-2001	Rodder et al.				July 5, 2001
9U	AH	US2002/0034865A1	03-21-2002	Umimoto et al.				Nov. 30, 2001
9U	AI	09/876,722		Scott				June 6, 2001
9U	AJ	10/133,193		McQueen et al.				April 26, 2002
	AK							
	AL							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country		Class	Subclass	Translation
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								No
	AM							
	AN							
	AO							
	AP							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
9U	AQ		Young et al., "A 0.13 μ m CMOS Technology with 193 nm Lithography and Cu/Low-k for High Performance Applications", IEDM, pgs. 563-566, April 2000.					
9U	AR		Yeh et al., "Optimum Halo Structure for Sub-0.1 μ m CMOSFETs", IEEE Transactions on Electronic Devices, Vol. 48, No. 10, October 2001, pgs. 2357-2362.					
9U	AS		Bouillon et al., "Re-examination of Indium implantation for a low power 0.1 μ m technology", IDEM, pgs. 897-900, 1995 (year is sufficient so that date is not in issue).					
EXAMINER			DATE CONSIDERED					
Jennifer M. Kennedy			Feb. 15, 2005					
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

1/3 IDS 11/13/03

Form PTO-144 				U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2356	SERIAL NO. 10/624,628	
				APPLICANT Luan C. Tran				
				FILING DATE July 21, 2003		GROUP 2812		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
QH	AA	6,144,079 A	11-2000	Shirahata et al.				
QH	AB	6,033,952	03-2000	Yasumura, et al.				
QH	AC	6,124,168	09-2000	Ong				
QH	AD	5,688,705	11-1997	Bergemont				
QH	AE	5,866,448	02-1999	Pradeep et al.				
QH	AF	5,858,847	01-1999	Zhou et al.				
QH	AG	6,380,598	04-2002	Chan				
QH	AH	6,060,364	05-2000	Maszara et al.				
QH	AI	6,194,276 B1	02-2001	Chan et al.				
QH	AJ	6,359,319 B1	03-2002	Noda				
QH	AK	5,164,806	11-1992	Nagatomo et al.				
QH	AL	4,937,756	06-1990	Hsu et al.				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
QH	AM	EP 0718881	06/96	EPO, Chan			Yes	No
	AN							
	AO							
	AP							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
QH	AR			Watanabe, H. et al., Novel 0.44μm ² Ti-Salicide STI Cell Technology for High-Density NOR Flash Memories and High Performance Embedded Application, IEEE 1998, pp. 36.2.1 - 36.2.4.				
QH	AS			Wolf, S., "Silicon Processing for the VLSI Era", Vol. 2, pp. 632-635.				
QH	AT			MITSUBISHI ELECTRIC WEBSITE: Reprinted from website http://www.mitsubishelectric.com/r_and_d/tech_showcase/s8.php on 3/29/2001: "8. Production Line Application of a Fine Hole Pattern-Formation Technology for Semiconductors", on 3/29/2001, 4 pgs				
EXAMINER <i>Jeffrey M. Kennedy</i>				DATE CONSIDERED <i>Feb 15, 2005</i>				
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								

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 Form PTO-148		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2356	SERIAL NO. 10/624,628		
		LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT Luan C. Tran			
				FILING DATE July 21, 2003	GROUP 2812		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
QH	AA	5,930,614	07-1999	Eimori et al.			
QH	AB	5,635,744	06-1997	Hidaka et al.			
QH	AC	6,204,536	03-2001	Maeda et al.			
QH	AD	6,515,899 B1	02-2003	Tu et al.			
QH	AE	4,570,331	02-1986	Eaton, Jr. et al.			
QH	AF	6,429,079 B1	08-2002	Maeda et al.			
QH	AG	6,607,979 B1	08-2003	Kamiyama			
QH	AH	4,686,000	08-1987	Heath			
QH	AI	5,814,875	09-1998	Kumazaki			
QH	AJ	5,654,573	08-1997	Oashi et al.			
QH	AK	6,479,330 B2	11-2002	Iwamatsu et al.			
QH	AL	6,586,803	07-2003	Hidaka et al.			
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	AN						No
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	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
QH	AR		CAHNERS SEMICONDUCTOR INTERNATIONAL WEBSITE: Reprinted from http://www.semiconductor.net/semiconductor/Issues/1999/sep99/docs/feature1.asp on 3/29/2001: "Resists Join the Sub-λ Revolution", 9 pgs.				
QH	AS		CAHNERS SEMICONDUCTOR INTERNATIONAL WEBSITE: Reprinted from http://www.semiconductor.net/semiconductor/Issues/1999/aug99/docs/lithography.asp on 3/29/2001: "Paths to Smaller Features", 1 pg.				
QH	AT		Wolf, S., "Silicon Processing for the VLSI Era, Vol. 1: Process Technology," Lattice Press 1986, pp. 434-437.				
EXAMINER		DATE CONSIDERED					Feb 15, 2005
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

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Sheet 3 of 3

Form PTO-1449 O I P E S C I E N C E P A T E N T & T R A D E M A R K O F F I C E NOV 1 3 2003		U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2356	SERIAL NO. 10/624,628		
LIST OF ART CITED BY APPLICANT (use several sheets if necessary)		APPLICANT Luan C. Tran					
		FILING DATE July 21, 2003		GROUP 2812			
U. S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
QH	AA	6,552,401 B1	04-2003	Dennison			
QH	AB	6,627,524 B2	09-2003	Scott			
QH	AC	US2002/0182829A1	12-2002	Chen			
QH	AD	US2002/0164846A1	11-2002	Lin et al.			Apr. 19, 2002
QH	AE	US2003/0071310A1	04-2003	Salling et al.			Oct. 11, 2001
	AF						
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FOREIGN PATENT DOCUMENTS							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
QH	AR		"Session 18: Integrated Circuits and Manufacturing - DRAM and Embedded DRAM Technology," 2001 IEDM Technical Program, 2001 IEEE International Electron Devices Meeting, Dec. 4, 2001, reprinted 11/15/01 from http://www.his.com/~iedm/techprogram/sessions/s18.html , pp. 1-2.				
	AS						
	AT						
EXAMINER	George M. Kennedy			DATE CONSIDERED		Feb. 15, 2005	
*EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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WELLS ST. JOHN, P.S.

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2356	SERIAL NO. 10/024623		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Lien C. Tran			
				FILING DATE July 21, 2003		GROUP 2011	
U.S. PATENT DOCUMENTS							
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GU	AA	6,521,487 B1	02-2003	Chen et al.			
GU	AB	6,492,444 B2	12-2002	Nobbe et al.			
GU	AC	6,468,865 B1	10-2002	Yang et al.			
GU	AD	6,451,704 B1	09-2002	Pradeep et al.			
GU	AB	6,436,747 B1	08-2002	Segwra et al.			
GU	AF	6,362,634 B1	03-2002	Sandford et al.			
GU	AG	6,277,720 B1	08-2001	Doddi et al.			
GU	AH	5,973,473	07-1999	Roland			
GU	AI	5,885,934	02-1999	Kodoh et al.			
GU	AJ	6,162,405 H1	01-2001	Yu et al.			
GU	AK	6,209,510 B1	03-2001	Ahmed et al.			
GU	AL	US2003/0030112A1	02-2003	Wada et al.			
FOREIGN PATENT DOCUMENTS							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Page, Etc.)							
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EXAMINER	DATE CONSIDERED						
Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							Feb 15, 2005

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WELLS ST. JOHN, P.S.

5098383424 P.03/03

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
N122-2336SERIAL NO.
10524,628LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Ivan C. TsoFILING DATE
July 21, 2003GROUP
2011

U.S. PATENT DOCUMENTS

*Examiner Initials		Document Number	Date	Name	Class	Section	Filing Date if Appropriate
AM		5,841,185	11-1998	Ishikawa			
AM		6,331,458 B1	12-2001	Aojima et al.			
AM		6,251,744 B1	06-2001	Su et al			
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FOREIGN PATENT DOCUMENTS

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AM								
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AO								
AP								
AO								

OTHER REFERENCES (including Author, Title, Date, Pertinent Page, etc.)

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EXAMINER Initial if reference considered

George M. Kennedy Feb. 15, 2005

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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WELLS ST. JOHN, P.S.

5098383424 P.03/03

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. NO22-1256	SERIAL NO. 10/624,629		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Lien C. Tran			
				PILING DATE July 21, 2003	GROUP 2811		
U.S. PATENT DOCUMENTS							
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CH	AA	5,767,537	06-1998	Kizilyalli			
CH	AB	5,369,215	11-1994	Vusal			
CH	AC	5,397,800	03-1995	Murichi			
CH	AD	5,493,728	04-1997	Hidaka			
CH	AE	5,672,526	09-1997	Kawamura			
CH	AF	5,223,714	07-1993	Wakamiya et al.			
CH	AG	5,440,161	08-1995	Iwamatsu et al.			
CH	AH	5,353,012	10-1994	Yamaguchi et al.			
CH	AI	5,830,226	01-1999	Wu			
CH	AJ	5,877,056	03-1999	Wu			
CH	AK	6,510,113 B1	02-2003	Beynon-Dill			
CH	AL	6,642,381 B2	11-2003	Matsuda et al.			
CH	AM	6,297,082 B1	10-2001	Lin et al.			
CH	AN	US2002/004392A1	04-2002	Maeda et al.			
CH	AO	US2002/0169231	10-2003	Clevenger et al.			
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	AR						
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AT							
EXAMINER <i>Jennifer M. Kennedy</i>		DATE CONSIDERED <i>Feb. 15, 2005</i>					
<small>*EXAMINER: initial if reference considered, whether or not citation is in conformance with MPEP 601; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							